

N-Channel Enhancement Mode MOSFET

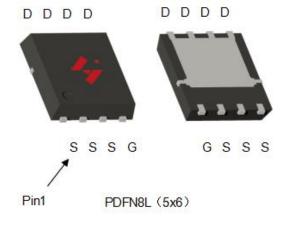
Feature

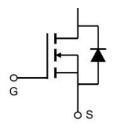
- 200V/31A
 R_{DS(ON)}=57mΩ (typ.) @ VGS = 10V
- 100% Avalanche Tested
- Reliable and Rugged
- Halogen Free and Green Devices Available (RoHS Compliant)

Applications

Power Switching application

Pin Description





N-Channel MOSFET

Ordering and Marking Information



Package Code C2 :PDFN8L (5x6)

Date Code
XYMXXXXXX

Note: HUAYI lead-free products contain molding compounds/die attach materials and 100% matte tin plateTermi-Nation finish; which are fully compliant with RoHS. HUAYI lead-free products meet or exceed the lead-Free requirements of IPC/JEDEC J-STD-020 for MSL classification at lead-free peak reflow temperature. HUAYI defines "Green" to mean lead-free (RoHS compliant) and halogen free (Br or Cl does not exceed 900ppm by weight in homogeneous material and total of Br and Cl does not exceed 1500ppm by weight).

HUAYI reserves the right to make changes, corrections, enhancements, modifications, and improvements to this pr-oduct and/or to this document at any time without notice.



Absolute Maximum Ratings

Symbol	Parameter	Rating	Unit	
Common Rat	tings (Tc=25°C Unless Otherwise Noted)		'	
VDSS	Drain-Source Voltage		200	V
Vgss	Gate-Source Voltage		±20	V
TJ	Maximum Junction Temperature		-55 to 175	°C
Тѕтс	Storage Temperature Range		-55 to 175	°C
ls	Source Current-Continuous(Body Diode) Tc=25°C		31	Α
Mounted on	Large Heat Sink		'	
IDM	Pulsed Drain Current *	Tc=25°C	120	А
			31	А
ID	Ib Continuous Drain Current	Tc=100°C	21	А
		Tc=25°C	125	W
Po	Maximum Power Dissipation	Tc=100°C 62.5		W
R_{θ} JC	Thermal Resistance, Junction-to-Case		1.2	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient **		50	°C/W
Eas	Single Pulsed-Avalanche Energy ***	L=0.3mH	161.8	mJ

Note: * Repetitive rating; pulse width limited by max. junction temperature.

Electrical Characteristics (Tc = 25°C Unless Otherwise Noted)

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Symbol	mbol Parameter Test Conditions		Min	Тур.	Max	Unit
Static Cha	racteristics					
BVDSS	Drain-Source Breakdown Voltage	V _{GS} =0V,I _{DS} =250μA	200	-	-	V
		V _{DS} =200V,V _{GS} =0V	-	-	1.0	μA
IDSS	I _{DSS} Drain-to-Source Leakage Current	TJ=125°C	-	-	50	μA
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _{DS} =250μA	3	3.7	5	V
Igss	Gate-Source Leakage Current	V _{GS} =±20V,V _{DS} =0V	-	-	±100	nA
RDS(ON)*	Drain-Source On-State Resistance	V _{GS} =10V,I _{DS} =20A	-	57	72	mΩ
Diode Cha	racteristics					
V _{SD} *	Diode Forward Voltage	Isp=20A,Vgs=0V	-	0.84	1.3	V
t rr	Reverse Recovery Time	lon=20	-	97.7	-	ns
Qrr	Reverse Recovery Charge	Isp=20A,dIsp/dt=100A/µs	-	424.7	-	nC

^{**} Surface mounted on FR-4 board.

^{***} Limited by TJmax, starting TJ=25°C, L = 0.3mH, VDS=160V, VGS =10V.



Electrical Characteristics (Cont.) (Tc =25°C Unless Otherwise Noted)

Symbol	Baramatar	Took Conditions	Test Conditions HY1420 Min Typ.	HY1420		Unit
	Parameter	lest Conditions		Max		
Dynamic	Characteristics		•			
Rg	Gate Resistance	V _{GS} =0V,V _{DS} =0V,F=1MHz	-	3.5	-	Ω
Ciss	Input Capacitance	V _{GS} =0V,	-	2570	-	
Coss	Output Capacitance	V _{DS} =25V,	_	199	-] pF
Crss	Reverse Transfer Capacitance	Frequency=1.0MHz		97	-	
td(ON)	Turn-on Delay Time		-	15.8	-	
Tr	Turn-on Rise Time	V _{DD} =100V,R _G =4Ω, I _{DS} =20A,V _{GS} =10V	-	39.7	-	
t d(OFF)	Turn-off Delay Time		-	33.4	-	ns
Tf	Turn-off Fall Time		-	35.3	-	
Gate Cha	rge Characteristics		•			
Qg	Total Gate Charge	V -460V V -40V	-	53	-	
Qgs	Gate-Source Charge	V _{DS} =160V, V _{GS} =10V,	-	15	-	nC
Qgd	Gate-Drain Charge	I _D =20A	-	19	-	

Note: *Pulse test, pulse width ≤ 300 us, duty cycle $\leq 2\%$



Typical Operating Characteristics

Figure 1: Power Dissipation

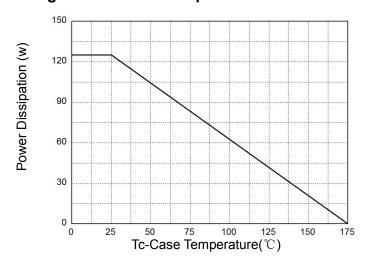


Figure 2: Drain Current

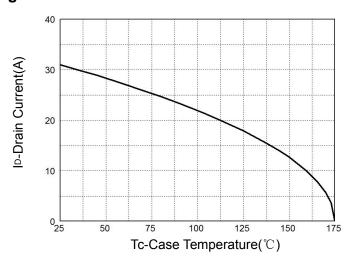


Figure 3: Safe Operation Area

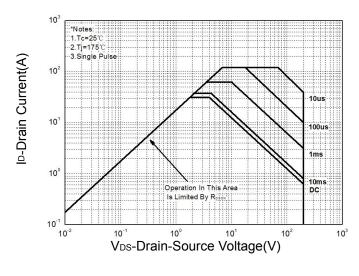


Figure 4: Thermal Transient Impedance

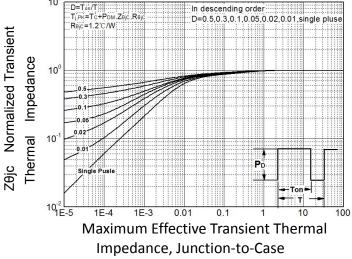


Figure 5: Output Characteristics

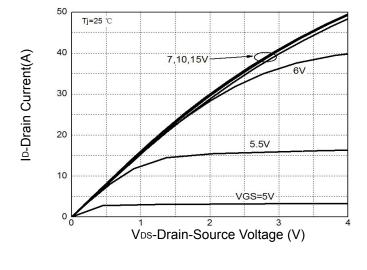
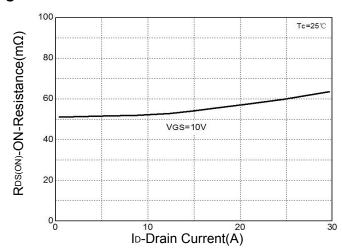


Figure 6: Drain-Source On Resistance





Typical Operating Characteristics(Cont.)

Figure 7: On-Resistance vs. Temperature

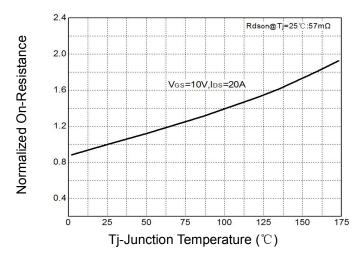


Figure 8: Source-Drain Diode Forward

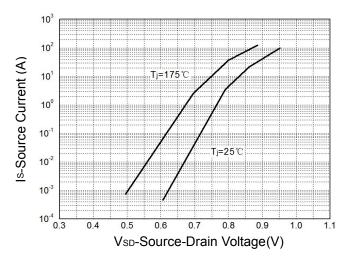


Figure 9: Capacitance Characteristics

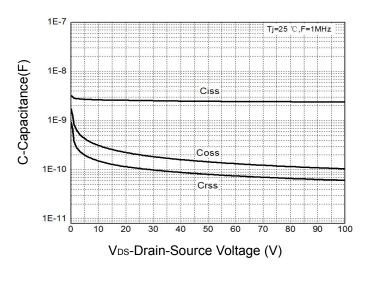
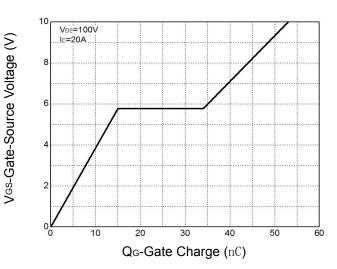
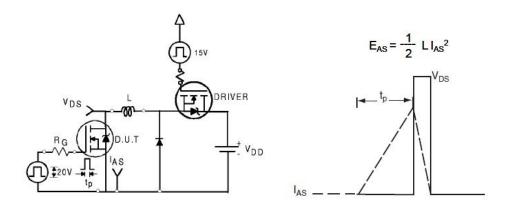


Figure 10: Gate Charge Characteristics

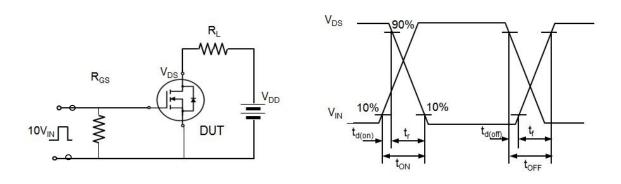




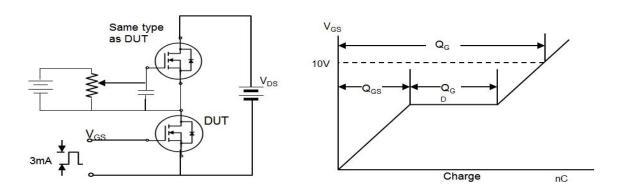
Avalanche Test Circuit and Waveforms



Switching Time Test Circuit and Waveforms



Gate Charge Test Circuit and Waveforms



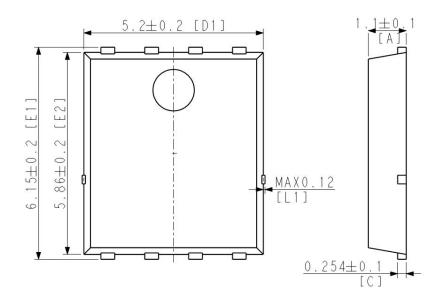


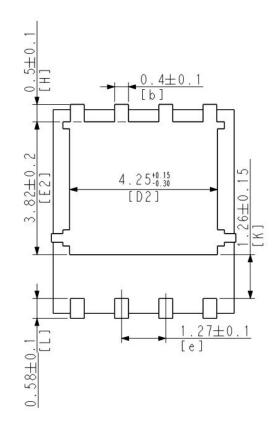
Device Per Unit

Package Type	Unit	Quantity
PDFN8L (5x6)	Reel	5000

Package Information

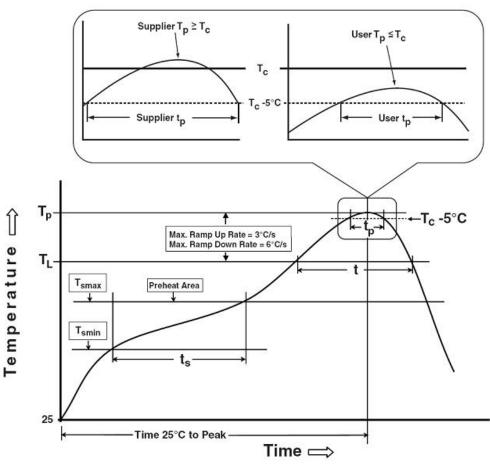
PDFN8L (5x6)







Classification Profile



Classification Reflow Profiles

Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly	
Preheat & Soak	100 °C	150 °C	
Temperature min (T _{smin})	150 °C	200 °C	
Temperature max (T _{smax})	60-120 seconds		
Time (Tsmin to Tsmax) (ts)	00-120 Seconds	60-120 seconds	
Average ramp-up rate	3 °C/accord may	3°C/second max.	
(T _{smax} to T _P)	3 °C/second max.		
Liquidous temperature (T _L)	183 °C	217 °C	
Time at liquidous (t₋)	60-150 seconds	60-150 seconds	
Peak package body Temperature	See Classification Temp in table 1	SeeClassification Tempin table 2	
(T _p)*	See Classification Temp in table 1		
Time (t _P)** within 5°C of the specified	20**	30** seconds	
classification temperature (T _c)	20** seconds		
Average ramp-down rate (Tpto Tsmax)	6 °C/second max.	6 °C/second max.	
Time 25°C to peak temperature	6 minutes max.	8 minutes max.	
*Tolerance for peak profile Temperature (T ₀) is defined as a supplier minimum and a user maximum.			

Tolerance for peak profile Temperature (Tp) is defined as a supplier minimum and a user maximum.

^{**} Tolerance for time at peak profile temperature (tp) is defined as a supplier minimum and a user maximum.

HY1420C2



Table 1.SnPb Eutectic Process – Classification Temperatures (Tc)

Package	Volume mm³	Volume mm³
Thickness	<350	≥350
<2.5 mm	235 °C	220 °C
≥2.5 mm	220 °C	220 °C

Table 2.Pb-free Process – Classification Temperatures (Tc)

Package	Volume mm³	Volume mm³	Volume mm³
Thickness	<350	350-2000	≥2000
<1.6 mm	260 °C	260 °C	260 °C
1.6 mm – 2.5 mm	260 °C	250 °C	245 °C
≥2.5 mm	250 °C	245 °C	245 °C

Reliability Test Program

Test item	Method	Description
SOLDERABILITY	JESD-22, B102	5 Sec, 245°C
PRECON	JESD-22, A113	30°C/60%/192Hrs
HTRB	JESD-22, A108	168Hrs//500Hrs/1000Hrs, Bias @ 150°C
HTGB	JESD-22, A108	168 Hrs/500Hrs/1000Hrs, V _{gs} 100% @ 150°C
PCT	JESD-22, A102	96 Hrs, 100%RH, 2atm, 121°C
TCT	JESD-22, A104	500 Cycles, -55°C~150°C

Customer Service

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